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 Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

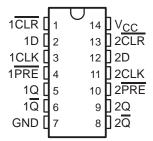
TYPE	TYPICAL MAXIMUM CLOCK FREQUENCY (C _L = 50 pF) (MHz)	TYPICAL POWER DISSIPATION PER FLIP-FLOP (mW)
'ALS74A	50	6
'AS74A	134	26

description

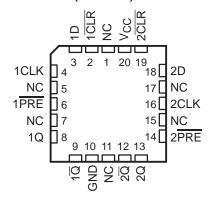
These devices contain two independent positive-edge-triggered D-type flip-flops. A low level at the preset (PRE) or clear (CLR) inputs sets or resets the outputs regardless of the levels of the other inputs. When PRE and CLR are inactive (high), data at the data (D) input meeting the setup-time requirements are transferred to the outputs on the positive-going edge of the clock (CLK) pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of CLK. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

The SN54ALS74A and SN54AS74A are characterized for operation over the full military temperature range of -55° C to 125° C. The SN74ALS74A and SN74AS74A are characterized for operation from 0° C to 70° C.

SN54ALS74A, SN54AS74A . . . J PACKAGE SN74ALS74A, SN74AS74A . . . D OR N PACKAGE (TOP VIEW)



SN54ALS74A, SN54AS74A . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

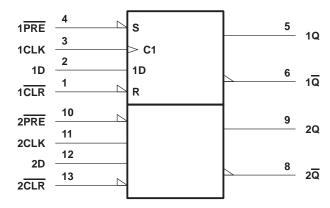
FUNCTION TABLE

	INP	OUTI	PUTS		
PRE	CLR	CLK	D	Q	Q
L	Н	Х	Х	Н	L
Н	L	X	Χ	L	Н
L	L	X	Χ	н†	H [†]
Н	Н	\uparrow	Н	Н	L
Н	Н	\uparrow	L	L	н
Н	Н	L	Х	Q_0	\overline{Q}_0

[†] The output levels in this configuration are not specified to meet the minimum levels for V_{OH} if the lows at PRE and CLR are near V_{IL} maximum. Furthermore, this configuration is nonstable; that is, it does not persist when PRE or CLR returns to its inactive (high) level.

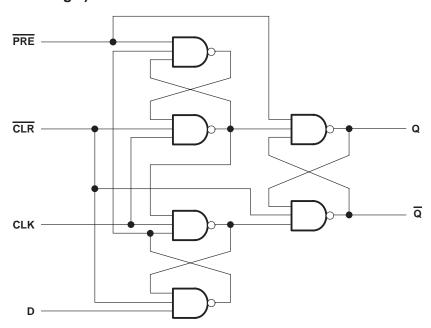
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logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, and N packages.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V _{CC}		7 V
Input voltage, V _I		7 V
	SN54ALS74A	
	SN74ALS74A	0°C to 70°C
Storage temperature range		-65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



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recommended operating conditions

			SN	SN54ALS74A		SN74ALS74A			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.7			0.8	V
ЮН	High-level output current				-0.4			-0.4	mA
loL	Low-level output current				4			8	mA
fclock	Clock frequency		0		25	0		34	MHz
		PRE or CLR low	15			15			
t _W	Pulse duration	CLK high	17.5			14.5			ns
		CLK low	17.5			14.5			
	0.4	Data	16			15			ns
t _{su}	Setup time before CLK↑	PRE or CLR inactive	10			10			115
t _h	Hold time after CLK↑	Data	2			0			ns
TA	Operating free-air temperature		-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED		TEST COL	TEST CONDITIONS		54ALS7	4A	SN	74ALS7	4A	UNIT
	PARAMETER	TEST COI	TEST CONDITIONS		TYP [†]	MAX	MIN	TYP†	MAX	UNII
VIK		V _{CC} = 4.5 V,	I _I = -18 mA			-1.5			-1.5	V
Vон		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V _{CC} -2	!		V _{CC} -2			V
V/01		V _{CC} = 4.5 V	I _{OL} = 4 mA		0.25	0.4		0.25	0.4	V
VOL		VCC = 4.5 V	$I_{OL} = 8 \text{ mA}$					0.35	0.5	V
1.	CLK or D	V _{CC} = 4.5 V,	V _I = 7 V			0.1			0.1	mA
l _I	PRE or CLR		VCC = 4.5 V,	V = 7 V			0.2			0.2
lu.	CLK or D	V 45V	V. 27V			20			20	^
IН	PRE or CLR	V _{CC} = 4.5 V,	V _I = 2.7 V			40			40	μΑ
I	CLK or D	V 45V	V- 0.4.V	T		-0.2			-0.2	A
¹ı∟	PRE or CLR	$V_{CC} = 4.5 V$	V _I = 0.4 V			-0.4			-0.4	mA
IO [‡]		V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
Icc		V _{CC} = 5.5 V,	See Note 1	T	2.4	4		2.4	4	mA

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C. ‡ The output conditions have been chosen to <u>produ</u>ce a current that closely approximates one half of the true short-circuit output current, l_{OS}. NOTE 1: I_{CC} is measured with D, CLK, and PRE grounded, then with D, CLK, and CLR grounded.

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switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C C _L R _L T _A	UNIT			
			SN54AI	LS74A	SN74AI		
			MIN	MAX	MIN	MAX	
f _{max}			25		34		MHz
t _{PLH}	PRE or CLR	Q or $\overline{\mathbb{Q}}$	3	18	3	13	ns
^t PHL	PRE OF CLR	Q or Q	5	17	5	15	115
t _{PLH}	CLK	Q or Q	5	23	5	16	ns
^t PHL	OLN	Q 01 Q	5	20	5	18	115

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Operating free-air temperature range, T _A : SN54AS74A	
SN74AS74A	0°C to 70°C
Storage temperature range	-65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			SI	N54AS74	A	SN74AS74A		UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.8			0.8	V
ЮН	High-level output current				-2			-2	mA
loL	Low-level output current				20			20	mA
f _{clock} *	Clock frequency		0		90	0		105	MHz
		PRE or CLR low	4			4			
t _W *	Pulse duration	CLK high	4			4			ns
		CLK low	5.5			5.5			
+ *	Out on the before OLKA	Data	4.5			4.5			ns
t _{su} *	Setup time before CLK↑	PRE or CLR inactive	2			2			115
th*	Hold time after CLK↑	Data	0			0			ns
TA	Operating free-air temperature	·	-55		125	0		70	°C

^{*} On products compliant to MIL-STD-833, Class B, this parameter is based on characterization data but is not production tested.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST COL	TEST CONDITIONS		54AS74	A	SN	174AS74	Α	UNIT
	PARAWEIER	TEST CONDITIONS		MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNII
٧IK		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2			-1.2	V
Vон		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V _{CC} -2			V _{CC} -2			V
VOL		$V_{CC} = 4.5 \text{ V},$	$I_{OL} = 20 \text{ mA}$		0.25	0.5		0.25	0.5	V
II		$V_{CC} = 5.5 \text{ V},$	V _I = 7 V			0.1			0.1	mA
1	CLK or D	V00 - 5 5 V	5.5 V, V _I = 2.7 V			20			20	
Ιн	PRE or CLR	V _{CC} = 5.5 V,				40			40	μΑ
1	CLK or D	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.5			-0.5	mA
IIL	PRE or CLR	vCC = 5.5 v,	V = 0.4 V			-1.8			-1.8	IIIA
IO [‡]	•	$V_{CC} = 5.5 V,$	$V_0 = 2.25 V$	-30		-112	-30		-112	mA
ICC	_	$V_{CC} = 5.5 \text{ V},$	See Note 1		10.5	16		10.5	16	mA

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C C _L R _L T _A	UNIT			
		, ,	SN54A	S74A	SN74A		
			MIN	MAX	MIN	MAX	
fmax*			90		105		MHz
t _{PLH}	PRE or CLR	0 0 7 0	2	9	2	7.5	ns
^t PHL	PRE OF CLR	Q or $\overline{\mathbb{Q}}$	2.5	11.5	2.5	10.5	115
^t PLH	CLK	Q or Q	2.5	10	3	8	ns
t _{PHL}	CLK	Q 01 Q	3.5	10.5	3	9	115

^{*} On products compliant to MIL-STD-833, Class B, this parameter is based on characterization data but is not production tested.

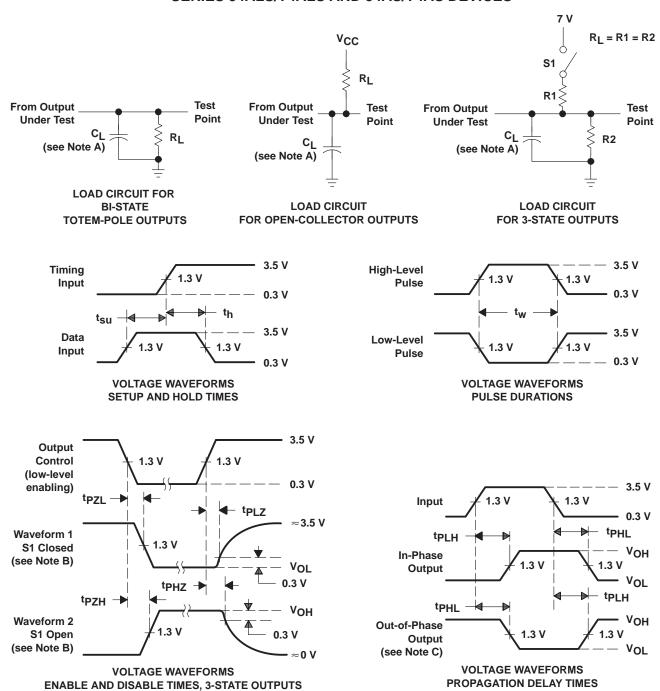


[‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, Ios. NOTE 1: Icc is measured with D, CLK, and PRE grounded, then with D, CLK, and CLR grounded.

[§] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

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PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR \leq 1 MHz, t_{Γ} = t_{f} = 2 ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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